

<b>Notic of References Cited</b>	Application/Control No. 10/059,635	Applicant(s)/Patent Under Reexamination WEI ET AL.	
	Examiner Simon J. Oh	Art Unit 1615	Page 1 of 1

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	B	US-6406738 B1	06-2002	Hogan et al.	427/2.14
	C	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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